

<b>Search Notes</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10662532	KOIDE ET AL.
	Examiner	Art Unit
	Nano, Sargon N	2157

### SEARCHED

Class	Subclass	Date	Examiner
709	203,204,218,223	8/3/2007	SN

### SEARCH NOTES

Search Notes	Date	Examiner
EAST (see report)	8/3/2007	SN
Consulted with SPE Saleh Najjar	8/1/2007	SN

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
709	203,204,218,223	8/3/2007	SN